

Modeling nanoscale imaging in electron microscopy

Deskripsi Lengkap: <https://lib.ui.ac.id/detail?id=20405933&lokasi=lokal>

Abstrak

This book presents the recent advances that have been made using mathematical methods to resolve problems in microscopy. With improvements in hardware-based aberration software significantly expanding the nanoscale imaging capabilities of scanning transmission electron microscopes (STEM), these mathematical models can replace some labor intensive procedures used to operate and maintain STEMs. This book, will also cover such relevant concepts as superresolution techniques, special denoising methods, application of mathematical/statistical learning theory, and compressed sensing.